



BSI Standards Publication

Semiconductor devices — Mechanical and climatic test methods

Part 15: Resistance to soldering temperature
for through-hole mounted devices

National foreword

This British Standard is the UK implementation of EN 60749-15:2010, incorporating corrigendum February 2011. It is identical to IEC 60749-15:2010. It supersedes BS EN 60749-15:2003, which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

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Amendments/corrigenda issued since publication

Date	Text affected
30 June 2011	Incorporation of CENELEC corrigendum February 2011: Modification of CENELEC Foreword